<u>Rules</u>

- 1. A candidate shall be declared passed in the examination if he/she secued at least 40% marks in internal assignment and external examination separately and 50% marks in aggregate.
- 2. A candidate is required to pass in theory as well as practical paper separately. A candidate who secure below 40% marks in internal or external examination in a paper. A candidate who secured 40% and above but below 50% marks (internal + external) in a paper will be declared failed.
- 3. A candidate who secure below 50% marks will be given D Grade and considered failed; a candidate who secured overall 50% marks and above but below 60% marks will be awarded grade C; a candidate who secures overall 60% marks and above but below 75% marks will be awarded grade B; a candidate who secures overall 75% marks and above marks will be awarded grade A in the mark sheet issued at final semester / year.

40% and above but below 50%	GRADE D	POOR
50% and above but below 60%	GRADE C	GOOD
60% and above but below 75%	GRADE B	VERY GOOD
75% and above	GRADE A	EXCELLENT

- 4. Despite the candidate being declared failed, he will be eligible to appear in the next semester/year examination. Due to paper will be treated as backlog paper (s). To clear the due paper (s) the candidate will be allowed to appear in the backlog paper (s) along with the next semester/yearly examination. If the candidate does not avail these opportunities or fails in these atempts his/her final semester/year result will be declared but mark sheet will not be issued.
- 5, No grace marks shall be awarded in internal assignments, practical paper & projects. The grace marks will be awarded only on aggregate marks of the theory paper upto 1% of the maximum of the two theory papers. No grace marks will be awarded in the due papers.
- 6. A candidate shall not be given any chance to improve the division/marks in any paper(s) in any semester/year.
- 7. Re-evaluation of answer book shall not be permissible. However, re-totaling is permitted as institutions rules.
- 8. In case of any mistake being detected in the preparation of mark sheet and brought to notice aferwards, the insstitutions will be fully empowered to correct the same.
- 9. The institution has the right to change any rule without any prior informamation.
- 10. The final semester/year mark sheet will show total marks of all the semester(s) of that course as well as whether the candidates has cleared all the semester(s) year or not.
- 11. Lateral Entry (LE) The Institution allows exemption regards to the duration and the numbers of paper of the course under Later Entry Scheme.
- 12. Candidate registered under Institution are of two categories i.e., Regular and OES. The candidate who is registered and studying regularly at the study centers come under regular category and candidate who are registered under open Education system come under OES category.
- 13. The candidate who is appearing at the examination or the fisst time (first atempt) is considered as fresh and the candidate who is appearing at the examination or the due paper(s) is considered as backlog.
- 14. Meaning of abbreviation used in the mark sheet is as given below :

P-Pass	F-Fail in aggregate	A Absent
DE - Due in external	PG-Pass with grade	DA-Due in assignment

15. All disputes relating to admission, study, Examination, issue of result, certificates and etc., are govered by Civil Laws and Civil Courts only subject to Chennai Jurisdiction.

L Technolo	OF SC OF SC OF SC	IEN RESULT CUM - CONS IENCE AND TECHNOLOGY	OLIDATED	MARKS (CARD	ECHNOLOG ECHNOLOG ID TECHNOLOG	
Name of the Candidate TEKI. GANESH Programme BSC ELECTRONICS Semester / Year Consolidated		DIAN INSTITUTE OF SC DIAN IN Father's Name DIAN IN FATHER'S Name DIAN IN D.O.B TE OF SC		TEKI.MALLIKARJUNARAC 07 - 05 - 1970			
						Consolidated	NDIAN INSTITUTE OF SC NDIAN IN Session OF SC
		Status NST	ITUTE OF SC			DIAN IN Roll No. OF SO	
Subject Code		Subject	Marks obtained	Minimu		Maximum	
HSE	TECHNICAL	ENGLISH TECHNOLOGY	DIAN 76	Ma UTE OF S	rks 50 NCE AN	Marks	
	MATHEMATI	IENCE AND TECHNOLOGY II	IDIAN INSTITUTION	UTE OF SE	0ENCE AN	ID TECHNOLOG	
IDIAN INS IDI RHY NST	PHYSICS	IENCE AND TECHNOLOGY	IDIAN INSTITUTION	UTE OF SC	1 ENCE AN	ID TECHNOLOG	
	CHEMISTRY	JENCE AND TECHNOLOGY	IDIAN INSTIT	UTE OF SC UTE OF SC	ENCE AN	ID TECHOLOG	
	COMPUTERPROGRAMMING		IDIAN 169 TITUTE OF SE		OENCE AN	ID TEC 100 LOG	
IDI GEE NST	DIGITAL SYSTEM DESIGN CHNOLOGY		IDIAN 160 TITUTE OF S50		0ENCE AN	ID TEC 100 LOG	
GEB	BASIC ELECTRICAL AND ELECTRONICS		IDIAN 179 TITUTE OF 50				
DI SIS INS IDIAN INST	SIGNALS & SYSTEMS AND TECHNOLOGY		IDIAN INSTIT	UTE OF SC			
IDIANENS IDIAN INST	ANALOG ELECTRONICS DIECHNOLOGY		IDIAN INSTIT	UTE OF SC	DIENCE AN	ID TECHNOLOG	
IDI GEP NST			IDIAN 16911 IDIAN INSTIT	UTE OF SC	CIENCE AN	ID TECHNOLOG	
	DIGITAL ELECTRONICS TECHNOLOGY		IDIAN INSTITUTE OF SC		VENCE AN	ID TECHNOLOG	
	COMMUNICATION SYSTEMS		IDIAN INSTIT			ID TEC100LOG	
IDIAN INST IDI AND NST	ELECTRO MAGNETIC THEORY THERMODYNAMICS AND TECHNOLOGY		IDIAN 173	73-11-15-50 76-11-15-50		ID TECHNOLOG ID TEC HOO LOG	
IDIAN INST IDI COE NST	TUTE OF SCIENCE AND TECHNOLOGY		IDIAN INSTIT	UTE OF SC		ID TECHNOLOG	
IDIAN INST			IDIAN INSTIT	UTE OF SC		ID TECHNOLOG	
IDIAN INST	CONTROL SYTEMSE AND TECHNOLOGY		IDIAN INSTIT	UTE OF SC		ID TECHNOLOG	
AWP	ANTENNA AND WAVE PROPAGATION		IDIAN 105 IDIAN 105 IDIAN 165	UTE OF SC			
	COMPUTER ARCHITECTURE AND ORG		IDIAN 163				
IDIAN INST	MICROPROCESSORS AND INTERFACING		IDIAN INSTITUDIAN INSTIT	UIE OF SU	DENCE AN	ID TECHNOLOG ID TEC 100 LOG	
IDIAN INST IDI MIC NST IDIAN INST IDIAN INST	MICROPROC	IENCE AND I ECHNOLOGY	IDIAN INSTIT IDIAN II 72 TIT IDIAN INSTIT IDIAN INSTIT	UTE OF SC UTE OF SC UTE OF SC	CIENCE AN CENCE AN CIENCE AN	ID TECHNOLOG ID TECI 100)LOG ID TECHNOLOG ID TECHNOLOG	
DIAN INST	ITUTE OF SC ITUTE OF SC ITUTE OF SC	IENCE AND TECHNOLOGY IN IENCE AND TECHNOLOGY IN IENCE AND TECHNOLOGY IN		UTE OF SC UTE OF SC UTE OF 10	SIENCE AN	ID TECHNOLOG	
DIVISION	ITUTE OF SC ITUTE OF SC		NDIAN INSTIT NDIAN INSTIT	UTE OF SC UTE OF SC	CIENCE AN		